### **EPC2023 – Enhancement Mode Power Transistor**

 $\overline{V}_{DS}$ , 30 V  $R_{DS(on)}\,,\,\,1.45\;m\Omega$ I<sub>D</sub>, 90 A









Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low R<sub>DS(on)</sub>, while its lateral device structure and majority carrier diode provide exceptionally low Q<sub>G</sub> and zero Q<sub>RR</sub>. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

	Maximum Ratings					
	PARAMETER VALUE					
\ \ \	Drain-to-Source Voltage (Continuous)	30	V			
V <sub>DS</sub>	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	36	V			
	Continuous ( $T_A = 25$ °C, $R_{\theta JA} = 6$ °C/W)	90	۸			
I <sub>D</sub>	Pulsed (25°C, $T_{PULSE} = 300 \mu s$ )	590	Α			
	Gate-to-Source Voltage	6	V			
V <sub>GS</sub>	Gate-to-Source Voltage	-4	V			
TJ	Operating Temperature -40 to 150		°C			
T <sub>STG</sub>	Storage Temperature	-40 to 150				

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EPC2023 eGaN® FETs are supplied only in passivated die form with solder bumps. Die Size: 6.05 mm x 2.3 mm

#### Applications:

- High Frequency DC-DC Conversion
- Point-of-Load (POL) Converters
- · Motor Drive
- Industrial Automation

Thermal Characteristics				
	PARAMETER	ТҮР	UNIT	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4		
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42		

Note 1: R<sub>BIA</sub> is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote\_Thermal\_Performance\_of\_eGaN\_FETs.pdf for details.

Static Characteristics (T <sub>J</sub> = 25°C unless otherwise stated)						
PARAMETER TEST CONDITIONS MIN TYP MAX UNIT						UNIT
$BV_DSS$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 1.3 \text{ mA}$	30			V
I <sub>DSS</sub>	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$		0.1	1	mA
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	V <sub>GS</sub> = 5 V		1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		0.1	1	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 20 \text{ mA}$	0.8	1.4	2.5	V
R <sub>DS(on)</sub>	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 40 \text{ A}$		1.15	1.45	mΩ
V <sub>SD</sub>	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A, } V_{GS} = 0 \text{ V}$		1.5		V

All measurements were done with substrate connected to source.

Dynamic Characteristics (T <sub>J</sub> = 25°C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance			2150	2600	
Coss	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}$		1530	2300	
$C_{RSS}$	Reverse Transfer Capacitance			100		pF
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0$ to 15 V, $V_{GS} = 0$ V		1850		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)	VDS = 0 to 13 V, VGS = 0 V		2020		
$R_{G}$	Gate Resistance			0.3		Ω
Q <sub>G</sub>	Total Gate Charge	$V_{DS} = 15 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 40 \text{ A}$		19	25	
$Q_{GS}$	Gate-to-Source Charge			5.7		
$Q_{GD}$	Gate-to-Drain Charge	$V_{DS} = 15 \text{ V}, I_D = 40 \text{ A}$		3.2		<b>"</b> C
$Q_{G(TH)}$	Gate Charge at Threshold			4		nC
Qoss	Output Charge	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}$		30	45	
$Q_{RR}$	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>. Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C

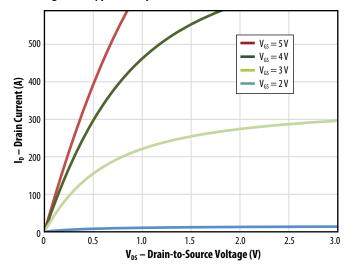


Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

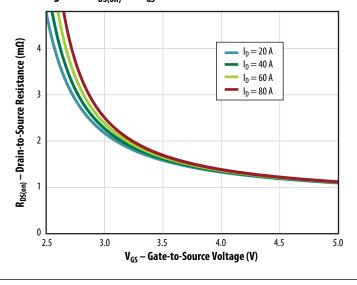


Figure 2: Transfer Characteristics

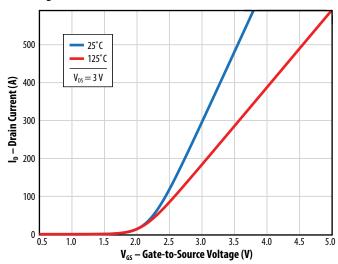


Figure 4: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

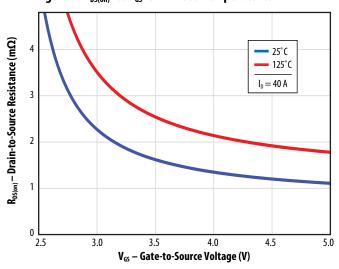


Figure 5a: Capacitance (Linear Scale)

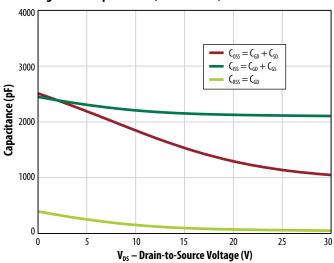


Figure 5b: Capacitance (Log Scale)

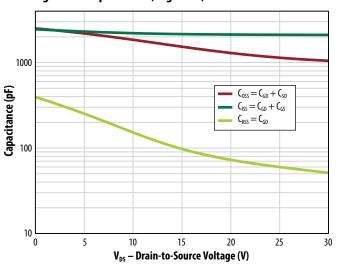


Figure 6: Output Charge and Coss Stored Energy

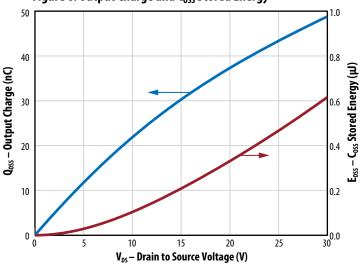
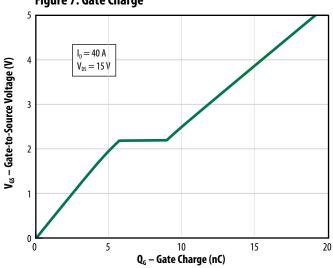
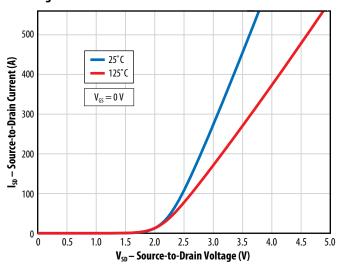
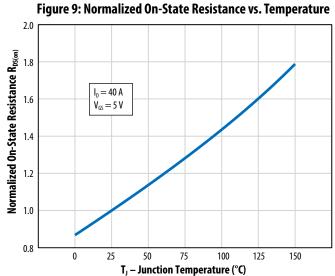


Figure 7: Gate Charge

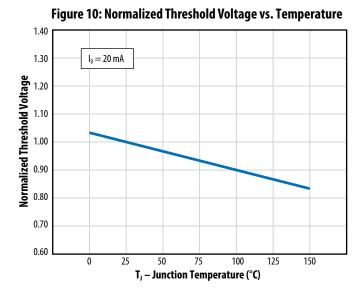


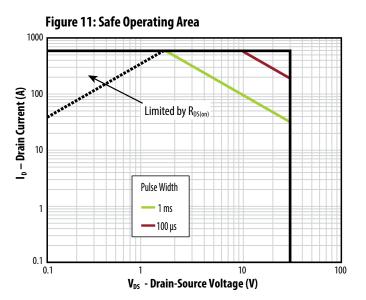
**Figure 8: Reverse Drain-Source Characteristics** 



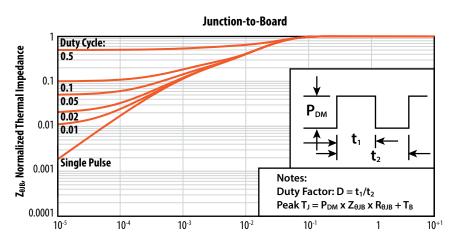


All measurements were done with substrate shortened to source

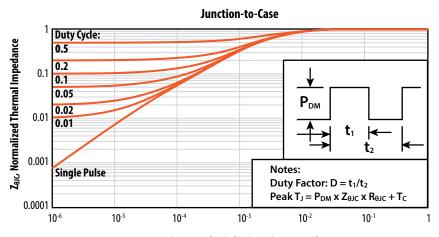




**Figure 12: Transient Thermal Response Curves** 

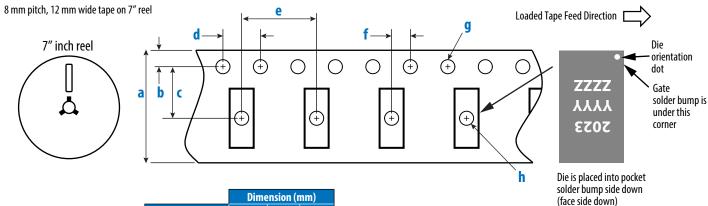


t<sub>p</sub>, Rectangular Pulse Duration, seconds



t<sub>p</sub>, Rectangular Pulse Duration, seconds

#### TAPE AND REEL CONFIGURATION

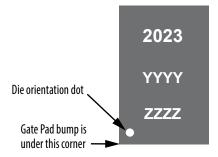


	Dimension (mm)			
EPC2023 (Note 1)	Target	MIN	MAX	
a	12.00	11.90	12.30	
b	1.75	1.65	1.85	
<b>c</b> (Note 2)	5.50	5.45	5.55	
d	4.00	3.90	4.10	
e	8.00	7.90	8.10	
f (Note 2)	2.00	1.95	2.05	
g	1.50	1.50	1.60	
h	1.50	1.50	1.75	

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

#### **DIE MARKINGS**

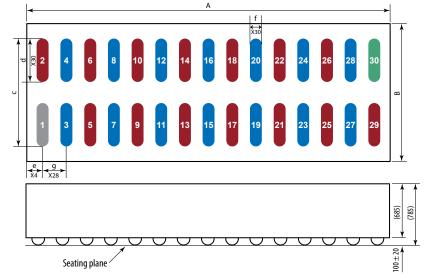


Part	Laser Markings			
Number	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3	
EPC2023	2023	YYYY	7777	

#### **DIE OUTLINE**

Side View

**Solder Bump View** 



	Micrometers				
DIM	MIN	Nominal	MAX		
Α	6020	6050	6080		
В	2270	2300	2330		
c	2047	2050	2053		
d	717	720	723		
e	210	225	240		
f	195	200	205		
g	400	400	400		

Pad 1 is Gate;

Pads 2,5,6,9,10,13,14,17,18,21,22,

25, 26, 29 are Source;

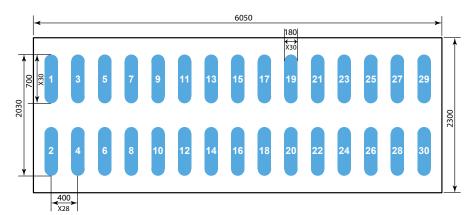
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;

Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

## RECOMMENDED LAND PATTERN

(units in µm)



Land pattern is solder mask defined Solder mask opening is 180 µm It is recommended to have on-Cu trace PCB vias

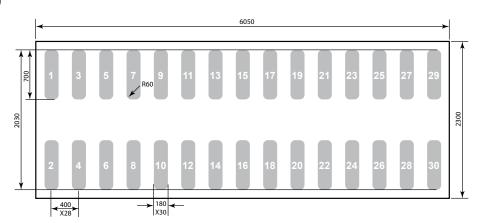
Pad 1 is Gate; Pads 2, 5, 6, 9,10,13,14, 17, 18, 21, 22, 25, 26, 29 are Source; Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;

Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

# RECOMMENDED STENCIL DRAWING

(units in µm)



Recommended stencil should be 4 mil (100  $\mu$ m) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at https://epc-co.com/epc/DesignSupport/ AssemblyBasics.aspx

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